

# Emil Manolov

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/11015362/publications.pdf>

Version: 2024-02-01

6  
papers

28  
citations

2258059

3  
h-index

2272923

4  
g-index

6  
all docs

6  
docs citations

6  
times ranked

51  
citing authors

#	ARTICLE	IF	CITATIONS
1	UV Sensitivity of MOS Structures with Silicon Nanoclusters. Sensors, 2019, 19, 2277.	3.8	7
2	Application of Metal-Oxide-Semiconductor structures containing silicon nanocrystals in radiation dosimetry. Open Physics, 2015, 13, .	1.7	8
3	Electrical Characterization of Interface Defects in MOS Structures Containing Silicon Nanoclusters. Advanced Materials Research, 2014, 976, 129-132.	0.3	1
4	Formation of Si Nanocrystals in Thin SiO <sub>2</sub> Films for Memory Device Applications. Materials Science Forum, 2010, 644, 101-104.	0.3	7
5	Radiation Dosimeter Based on Metal-Oxide-Semiconductor Structures Containing Silicon Nanocrystals. Key Engineering Materials, 0, 495, 120-123.	0.4	5
6	Electrical Characterization of MOS Structures with Silicon Nanocrystals Suitable for X-Ray Detection. Key Engineering Materials, 0, 543, 150-153.	0.4	0